



Keynote speaker:

Dr. Ephraim Suhir,
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Presentation:

**" Solder Joint Interconnections in Automotive Electronics:
Design-for-Reliability and Accelerated Testing"**

Dr. Suhir is Life Fellow of IEEE; Fellow of the American Society of Mechanical Engineers (ASME), American Physical Society (APS), Institute of Physics (UK), Society of Optical Engineers (SPIE), International Microelectronics and Packaging Society (IMAPS), the Society of Plastics Engineers (SPE); Associate Fellow of the American Institute of Aeronautic and Astronautic (AIAA); and Foreign Full Member (Academician) of the National Academy of Engineering, Ukraine, the country where he was born.

Dr. Suhir has authored about 300 publications (patents, books, book chapters, papers), presented many keynote and invited talks worldwide and received numerous professional awards, including 1996 Bell Labs Distinguished Member of Technical Staff Award for developing methods to predict the reliability of AT&T and Lucent Technologies products; 2000 IEEE-CPMT Outstanding Sustained Technical Contribution Award for outstanding and continuing contributions to the technologies in fields encompassed by the CPMT Society; and 2004 ASME Worcester Read Warner Medal for outstanding contributions to the permanent literature of engineering. He is the third Russian American, after Steven Timoshenko and Igor Sikorsky, who received this prestigious award.